

<b>Notice of References Cited</b>	Application/Control No. 10/556,530		Applicant(s)/Patent Under Reexamination INOUE ET AL.	
	Examiner MICHAEL WILSON		Art Unit 1794	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0055013 A1	05-2002	Kim et al.	428/690
*	B	US-2002/0132134 A1	09-2002	Hu et al.	428/690
*	C	US-2003/0039838 A1	02-2003	Chen et al.	428/411.1
*	D	US-2004/0023060 A1	02-2004	Kim et al.	428/690
*	E	US-7,429,425 B2	09-2008	Ikeda et al.	428/690
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.